



## **Schedule of Scope to Certificate of Conformity Approved Process**

**IECQ Certificate No.: IECQ-L ULTW 09.0014**

**CB Certificate No.: 20000991 ITL**

**Schedule Number: IECQ-L ULTW 09.0014-S      Rev No.: 6      Revision Date: 2019/05/12      Page 1 of 2**

### **Appendix-1 (20000991 ITL) Schedule of Scope to Certificate of Approval**

**1. Reliability Test (International standards, including JEDEC, IPC, EIA, AEC, MIL, ...etc.):**

<b>Test Items</b>	<b>Standard/Method</b>
Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices	IPC/JEDEC / J-STD-020
Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing	JEDEC / JESD22-A113
High Temperature storage Life	JEDEC / JESD22-A103
Low Temperature Storage Life	JEDEC / JESD22-A119
Steady State Temperature Humidity Bias Life Test	JEDEC / JESD22-A101
Highly-Accelerated Temperature and Humidity Stress Test (HAST)	JEDEC / JESD22-A110
Accelerated Moisture Resistance-Unbias Autoclave	JEDEC / JESD22-A102
Thermal Shock	JEDEC / JESD22-A106
Temperature Cycling	JEDEC / JESD22-A104
Salt Atmosphere	JEDEC / JESD22-A107
Lead Integrity	JEDEC / JESD22-B105
Solderability	JEDEC / JESD22-B102
Wetting Balance Solderability	MIL-STD-883 / Method 2022
Solder Ball Shear	JEDEC / JESD22-B117
Mechanical Shock	JEDEC / JESD22-B110
Vibration	JEDEC / JESD22-B103

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**DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan**





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<b>Pull/Push Test</b>	<b>Base on Customer's requirements</b>
<b>Bent/Contact Durability Test</b>	<b>Base on Customer's requirements</b>
<b>Drop Test</b>	<b>Base on Customer's requirements</b>
<b>Twist Test</b>	<b>Base on Customer's requirements</b>

**2. Failure Analysis of integrated circuits, including Electrical Analysis, Optical Microscope, Scanning Acoustic Tomograph (SAT), Cross Section, Decap, Scanning Electron Microscope (SEM)/ Energy Dispersive Spectrometer (EDS), ...etc.**

Technical Reviewer of DQS: \_\_\_\_\_ Date: 5/12/2019

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